

Integration of a Metasurface with a Photonic Chip Enables Free-Space Light Projection with Arbitrary Polarization

Alexander Yulaev*^(1,2), Wenqi Zhu^(1,3), Cheng Zhang^(1,3), Daron A. Westly⁽¹⁾, Henri J. Lezec⁽¹⁾, Amit Agrawal^(1,3), and Vladimir Aksyuk⁽¹⁾

- (1) Physical Measurement Laboratory, National Institute of Standards and Technology, Gaithersburg, MD 20899, USA; e-mail: alexander.yulaev@nist.gov; wenqi.zhu@nist.gov; cheng.zhang@nist.gov; daron.westly@nist.gov; henri.lezec@nist.gov; amit.agrawal@nist.gov; vladimir.aksyuk@nist.gov
 (2) Department of Chemistry and Biochemistry, University of Maryland, College Park, MD 20742, USA
 (3) Maryland Nanocenter, University of Maryland, College Park, MD 20742, USA

Photonic systems being integrated with mechanical, biological, and chemical systems, where phase, intensity, and polarization of light radiation are well-controlled, pave the way for chip-scale optical materials spectroscopy [1], molecular and atomic physics [2], and optical manipulation [3]. A photonic extreme mode converter (EMC), that we have recently realized, emits a $\approx 200 \mu\text{m}$ wide collimated Gaussian beam from a single-mode waveguide (WG) into free-space [4,5]. The radiated linearly polarized beam stays collimated over several millimeters with low diffraction. Here we demonstrate integration of the developed EMC with a planar metasurface (MS), enabling efficient conversion of light from a single-mode photonic waveguide into free-space with arbitrarily-defined spatially-dependent wavefront and polarization state. In our design, 780 nm light is converted from an on-chip photonic mode to a free-space mode via 3 consecutive stages (Fig. 1a): (i) a WG mode expansion into a slab mode via evanescent coupling, slab mode projection to a linear polarized 2D Gaussian beam using an apodised grating, and then light focusing and polarization conversion from linear to elliptical processed by a flat MS.

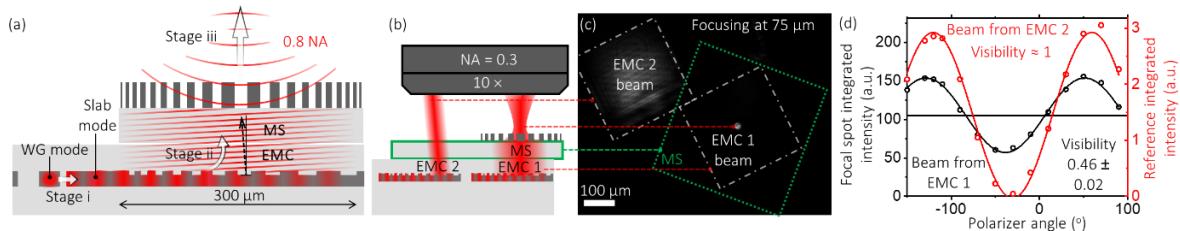


Figure 1. A photonic platform and characterization of free-space light. (a) Device operation. (b) Experimental apparatus. (c) An optical image showing free-space MS-processed and reference beams. (d) Light intensity of free-space reference (red) and MS-processed (black) radiation vs. polarizer orientation.

To test the performance of our photonic platform, we collect light processed by a MS and linear polarized radiation from a similar EMC 2 within the same field of view (Fig. 1 b,c). Polarization of both beams is estimated based on light transmission vs. polarizer orientation and shows an elliptical polarized beam modified by a MS (Fig. 1d). Analysis of the focal spot acquired using 100 \times objective (NA = 0.9) reveals the symmetric and aberration-free shape with 445 nm full width at half maximum based on a Gaussian fit.

To conclude, we have developed an integrated photonic platform made of a planar MS and an EMC, that radiates free space light with well-controlled light properties. Our device opens new avenues for miniaturized atomic sensors with essential need for atomic vapor interacting with circular polarized focusing light beams.

References

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